

RESPONSE UNDER 37 C.F.R. §1.116  
EXPEDITED PROCEDURE - EXAMINING GROUP 2800

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

|                                      |   |                           |
|--------------------------------------|---|---------------------------|
| In re Application                    | ) | <u>PATENT APPLICATION</u> |
|                                      | ) |                           |
| Inventors: Frederick Ware, et al.    | ) |                           |
|                                      | ) |                           |
| Application No.: 10/768,443          | ) | Art Unit: 2829            |
|                                      | ) |                           |
| Filed Date: Jan. 30, 2004            | ) | Examiner: Nguyen, T.      |
|                                      | ) |                           |
| Title: METHOD AND APPARATUS FOR TEST | ) | Customer No.: 38456       |
| CHARACTERIZATION OF SEMICONDUCTOR    | ) |                           |
| COMPONENTS                           | ) |                           |
| <hr/>                                |   |                           |

RESPONSE TO OFFICE ACTION UNDER 37 C.F.R. §1.116

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This RESPONSE is in reply to the outstanding Office action.

**AMENDMENTS to the CLAIMS** begin on Page 2 of this RESPONSE.

**REMARKS** begin on Page 28 of this RESPONSE.